



SHEET 1 OF 1

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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  <b>(PTO-1449)</b>				ATTY. DOCKET NO. <b>60188-725</b>	SERIAL NO. <b>Continuation of Appl. N. 09/381,377</b>	
<b>APPLICANT</b> <b>Mitsuyasu OHTA, et al.</b>						
<b>FILING DATE</b> <b>January 06, 2004</b>				<b>GROUP</b>		
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number +-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation
						Yes
/CB/		JP 62-62275	18/03/87			No
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/CB/		JP 5-158724	25/06/93			
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				
/CB/		Y. ZORIAN, "Test Requirements for Embedded Core-Based Systems and IEEE P1500", International Test Conference Proceedings, 11/01/1997 – 11/06/1997, pages 191-199.				
/CB/		M. ABRAMOVICI, "Design For Testability Techniques: A Comparative Analysis", June 2002, USPTO Lecture.				
<b>EXAMINER</b> <b>/Cynthia Bmtv</b>				<b>DATE CONSIDERED</b> <b>04/25/2007</b>		

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